

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. IMEC88.001CP1	APPLICATION NO. 09/157,655
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Dierickx et al.	
		FILING DATE September 21, 1998	GROUP 2711-2878



U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
TXL	4,473,836	9/25/84	Chamberlain	257	290	—
TXL	4,565,756	1/21/86	Needs	430	7	—
TXL	4,580,103	4/1/86	Tompsett	330	9	—
TXL	4,647,975	3/3/87	Alston et al.	348	222	—
TXL	5,146,074	9/8/92	Kawahara et al.	250	208,1	—
TXL	5,153,420	10/6/92	Hack et al.	250	208,1	—
TXL	5,164,832	11/17/92	Halvis et al.	348	250	—
TXL	5,258,845	11/2/93	Kyuma et al.	348	299	—
TXL	5,296,696	3/22/94	Uno	250	208,1	—
TXL	5,321,528	6/14/94	Nakamura	358	482	—
TXL	5,335,008	8/2/94	Hamasaki	348	301	—
TXL	5,608,204	3/4/97	Hofflinger et al.	250	208,1	—
TXL	5,614,744	3/25/97	Merrill	257	291	—
TXL	3,904,818	9/9/75	Kovac	348	243	—
TXL	4,253,120	2/24/81	Levine	348	246	—

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
TXL	548 987	6/30/93	Europe	—	—		
TXL	657 863	6/14/95	Europe	—	—		
TXL	739 039	10/23/96	Europe	—	—		
TXL	93/19489	9/30/93	PCT	—	—		
TXL	635 973	1/25/95	Europe	—	—		
TXL	260 954	3/23/88	Europe	—	—		
TXL	354 106	7/2/90	Europe	—	—		
TXL		4/8/98	European Search Report	—	—		

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
TXL	Aoki et al.. "A Collinear 3-Chip Image Sensor". <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 102-103.
	Horii et al.. "A 490 x 404 Element Imager for a Single-Chip Color Camera". <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 96-97.
	Nagakawa et al.. "A 580 x 500-Element CCD Imager with a Shallow Flat P Well". <u>IEEE International Solid-State Circuits Conference</u> , 1985, pp. 98-99.
	Mahowald, M.A.. "Silicon Retina with Adaptive Photoreceptors". <u>SPIE</u> , Vol. 1473, 1991, pp. 52-58.

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EXAMINER INITIAL <i>TXL</i> 	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
	Mann, J. "Implementing Early Visual Processing In Analog VLSI: Light Adaptation". <u>SPIE</u> , Vol 1473. 1991. pp. 128-136.	
	Ono et al., "Analysis of Smear Noise In Interline-CCD Image Sensor with Gate-Free Isolation Structure". Abstract of the 1991 Int'l Conference on Solid State Devices and Materials, Yokohama, 1991. pp. 68-70.	
	Yadid-Pecht et al., "A Random Access Photodiode Array for Intelligent Image Capture". <u>IEEE Transactions on Electron Devices</u> , Vol. 38, No. 8 August 1991.	
	Ricquier et al., "Pixel Structure with Logarithmic Response for Intelligent and Flexible Imager Architectures". <u>Microelectronic Engineering</u> , 19 (1992). pp. 631-634	
	Sevenhuijsen, et al., "A 400mm Long Linear X-Ray Sensitive Image Sensor". <u>IEEE International Solid-State Circuits Conference</u> , 1987. pp. 108-109.	
	Anderson, S. et al., "A Single Chip Sensor & Image Processor or Fingerprint Verification". <u>IEEE 1991 Custom Integrated Circuits Conference</u> , May 12-15, 1991. pp. 12.1.1-12.1.4.	
	Dierickx, Bart, "XYW Detector: A Smart Two-Dimensional Particle Sensor". <u>Nuclear Instruments and Methods in Physics Research A275</u> , North-Holland Physics Publishing Division, 1989. pp. 542-544.	
	Klein, P., "Design and Performance of Semiconductor Detectors with Integrated Amplification and Charge Storage Capability". <u>Nuclear Instruments and Methods in Physics Research A305</u> , 1991. pp. 517-526.	
	Aw, Chye Huat, et al., "A 128 x 128-Pixel Standard-CMOS Image Sensor with Electronic Shutter". <u>IEEE Journal of Solid State Circuits</u> , Vol.31, No. 12, December 1996. pp. 1922-1930.	
Martin, W.J. et al., "Dynamic Offset Null". <u>IBM Technical Disclosure Bulletin</u> , No. 23, No. 9, February 1981. pp. 4195-4196.		

EXAMINER 	DATE CONSIDERED <i>6/00</i>
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

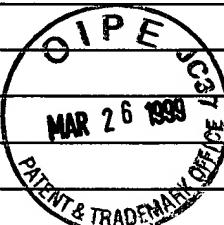
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
TXL	5,841,126	11/24/98	Fossum	—	—	



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FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	2324651	28/10/98	Great Britain				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
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